



Product Change Notification / BLAS-15MFGB667

Date:

16-Aug-2023

Product Category:

Simple and Complex Programmable Logic

PCN Type:

Manufacturing Change

Notification Subject:

CCB 6478 Initial Notice: Qualification of NSEB as an additional assembly site for selected ATF22LV10C, ATF22LV10CQZ, ATF22V10C, ATF22V10CQZ, ATF750CL and ATF750LVC device families available in 24L TSSOP (4.4mm) package.

Affected CPNs:

[BLAS-15MFGB667_Affected_CPN_08162023.pdf](#)

[BLAS-15MFGB667_Affected_CPN_08162023.csv](#)

Notification Text:

PCN Status:Initial Notification

PCN Type:Manufacturing Change

Microchip Parts Affected:Please open one of the files found in the Affected CPNs section.

Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change:Qualification of NSEB as an additional assembly site for selected ATF22LV10C, ATF22LV10CQZ, ATF22V10C, ATF22V10CQZ, ATF750CL and ATF750LVC device families available in 24L TSSOP (4.4mm) package.

Pre and Post Change Summary:

BLAS-15MFGB667 - CCB 6478 Initial Notice: Qualification of NSEB as an additional assembly site for selected ATF22LV10C, ATF22LV10CQZ, ATF22V10C, ATF22V10CQZ, ATF750CL and ATF750LVC device families available in 24L TSSOP (4.4mm) package.

Affected Catalog Part Numbers (CPN)

ATF22LV10C-10XU

ATF22LV10CQZ-30XU

ATF22LV10CQZ-30XU-T

ATF22V10C-10XU

ATF22V10CQZ-20XU

ATF22V10CQZ-20XU-044

ATF750CL-15XU

ATF750LVC-15XU



QUALIFICATION PLAN SUMMARY

PCN #: BLAS-15MFGB667

**Date:
August 3, 2023**

**Qualification of NSEB as an additional assembly site for selected
ATF22LV10C, ATF22LV10CQZ, ATF22V10C, ATF22V10CQZ,
ATF750CL and ATF750LVC device families available in 24L TSSOP
(4.4mm) package.**

Purpose: Qualification of NSEB as an additional assembly site for selected ATF22LV10C, ATF22LV10CQZ, ATF22V10C, ATF22V10CQZ, ATF750CL and ATF750LVC device families available in 24L TSSOP (4.4mm) package.

CCB #: 6478

<u>Misc.</u>	Assembly site	NSEB
	BD Number	BD-001628-01
	MP Code (MPC)	197117NSBC02
	Part Number (CPN)	ATF750CL-15XU
	MSL information	MSL 2
	Assembly Shipping Media (T/R, Tube/Tray)	Tube
	Base Quantity Multiple (BQM)	62 units/tube
	Reliability Site	MPHIL
<u>Lead-Frame</u>	Paddle size	118x217
	Material	C7025
	DAP Surface Prep	Spot Plating
	Treatment	Non-Rough
	Process	Etched
	Lead-lock	No
	Part Number	FI0058
	Lead Plating	Matte Tin
	Strip Size	50.8x210 mm
Strip Density	70	
<u>Bond Wire</u>	Material	Au
<u>Die Attach</u>	Part Number	8200T
	Conductive	Yes
<u>MC</u>	Part Number	G605L
<u>PKG</u>	Package Type	TSSOP
	Pin/Ball Count	24
	PKG width/size	4.4mm

Test Name	Conditions	Sample Size	Min. Qty of Spares per Lot (should be properly marked)	Qty of Lots	Total Units	Fail Accept Qty	Est. Dur. Days	ATE Test Site	REL Test Site	Special Instructions
Standard Pb-free Solderability	J-STD-002D ; Perform 8 hour steam aging for Matte tin finish and 1 hour steam aging for NiPdAu finish prior to testing. Standard Pb-free: Matte tin/ NiPdAu finish, SAC solder, wetting temp 245°C for both SMD & through hole packages.	22	5	1	27	> 95% lead coverage	5		MPHIL	Standard Pb-free solderability is the requirement. SnPb solderability (backward solderability- SMD reflow soldering) is required for any plating related changes and highly recommended for other package BOM changes.
Wire Bond Pull - WBP	Mil. Std. 883-2011	5	0	1	5	0 fails after TC	5		MPHIL	30 bonds from a min. 5 devices.
Wire Bond Shear - WBS	CDF-AEC-Q100-001	5	0	1	5		5		MPHIL	30 bonds from a min. 5 devices.
Wire Sweep									MPHIL	Required for any reduction in wire bond thickness.
Physical Dimmensions External Visual	Measure per JESD22 B100 and B108 Mil. Std. 883-2009/2010	10	0	3	30		5		MPHIL	
	All devices prior to submission for qualification testing		0	3	ALL	0	5		MPHIL	
Preconditioning - Required for surface mount devices	JESD22-A113. +150°C Bake for 24 hours, moisture loading requirements per MSL level + 3X reflow at peak reflow temperature per Jedec-STD-020E for package type; Electrical test pre and post stress at +25°C. MSL2/260	231	15	3	738	0	15	MPHIL	MPHIL	Spares should be properly identified. 77 parts from each lot to be used for HAST, uHAST, Temp Cycle test.
HAST	JESD22-A110. +130°C/85% RH for 96 hours or 110°C/85%RH for 264 hours. Electrical test pre and post stress at +25°C and hot temp (85°C).	77	5	3	246	0	10	MPHIL	MPHIL	Spares should be properly identified. Use the parts which have gone through Pre-conditioning.
UHAST	JESD22-A118. +130°C/85% RH for 96 hrs or +110°C/85% RH for 264 hrs. Electrical test pre and post stress at +25°C	77	5	3	246	0	10	MPHIL	MPHIL	Spares should be properly identified. Use the parts which have gone through Pre-conditioning.
Temp Cycle	JESD22-A104. -65°C to +150°C for 500 cycles. Electrical test pre and post stress at hot temp (85°C); 3 gram force WBP, on 5 devices from 1 lot, test following Temp Cycle stress.	77	5	3	246	0	15	MPHIL	MPHIL	Spares should be properly identified. Use the parts which have gone through Pre-conditioning.

CCB 6478
Pre and Post Change Summary
PCN# BLAS-15MFGGB667



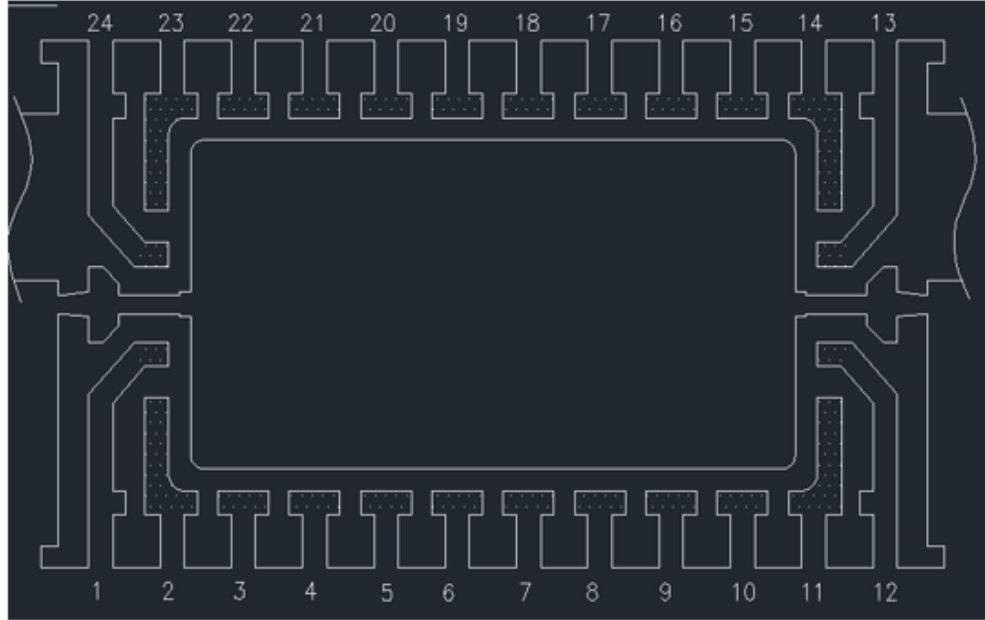
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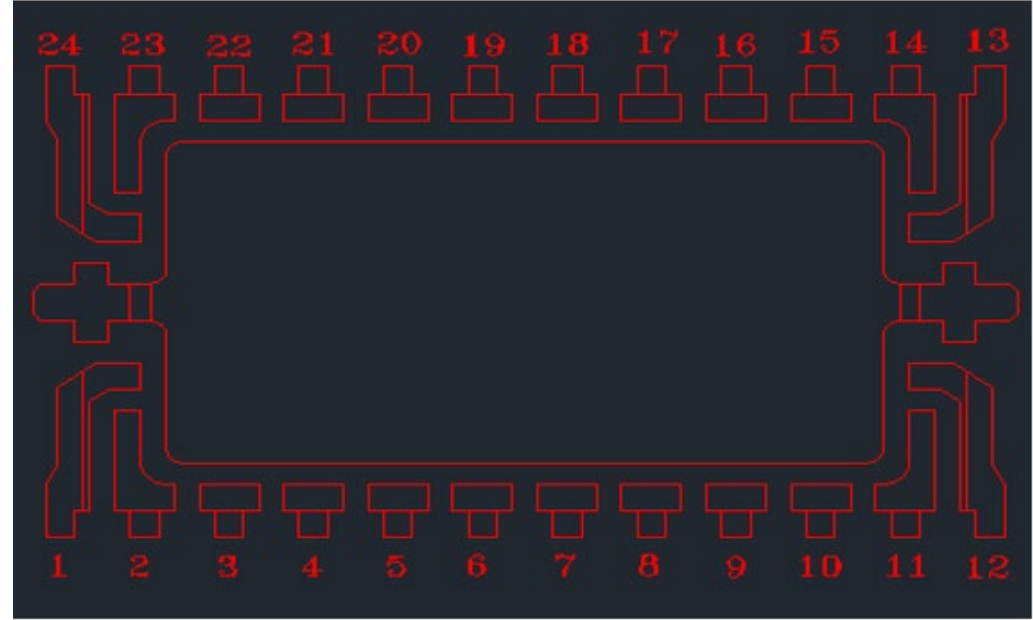
LEAD FRAME COMPARISON

LPI



Note: Not to scale

NSEB



Note: Not to scale

TUBE COMPARISON

LPI



Note: Not to scale

Tube Length (mm)	515+/-1.5
Tube Width (mm)	8.45+0.05/-0.07
Tube Opening (mm)	6.9+0.15
Tube Thickness (mm)	3.0+/-0.15

NSEB



Note: Not to scale

Tube Length (mm)	max: 509.27 min: 506.73
Tube Width (mm)	7.92 max
Tube Opening (mm)	6.93+/-0.076
Tube Thickness (mm)	3.12 max